




# Power MOSFETS

## DATASHEET

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**LM40072NAP3A**

N-Channel  
Enhancement Mode MOSFET

 Leadpower-semiconductor Corp., Ltd

 [sales@leadpower-semi.com](mailto:sales@leadpower-semi.com)

 (03) 6577339 FAX : (03) 6577229

 [www.leadpower-semi.com](http://www.leadpower-semi.com)



Quality Management Systems

ISO 9001:2015 Certificate


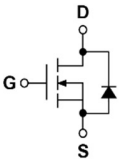
# LM40072NAP3A



## N-Channel Enhancement Mode MOSFET

### Pin Description

### Product Summary

<b>TO-220-3L</b> 	<b>Symbol</b> 	<b>Symbol</b>	<b>N-Channel</b>	<b>Unit</b>
		V <sub>DSS</sub>	40	V
		R <sub>DS(ON)-Max</sub>	7.2	mΩ
		I <sub>D</sub>	91	A

### Feature

- Fast switching speed
- Reliable and Rugged
- ROHS Compliant & Halogen-Free
- 100% UIS and Rg Tested

### Applications

- Switching Mode Power Supply
- Power tools

### Ordering Information

Orderable Part Number	Package Type	Form	Shipping	Marking
LM40072NAP3A	TO-220-3L	Tube	50/ Tube	40072 □□□□□□

Note : □□□□□□ = Lot Code

### Absolute Maximum Ratings (T<sub>J</sub>=25°C Unless Otherwise Noted)

Symbol	Parameter	N-Channel	Unit	
V <sub>DSS</sub>	Drain-Source Voltage	40	V	
V <sub>GSS</sub>	Gate-Source Voltage	±20		
T <sub>J</sub>	Maximum Junction Temperature	150	°C	
T <sub>STG</sub>	Storage Temperature Range	-55 to 150	°C	
I <sub>S</sub>	Diode Continuous Forward Current	T <sub>C</sub> =25°C	54	A
I <sub>DM</sub> <sup>①</sup>	Pulse Drain Current Tested	T <sub>C</sub> =25°C	227	A
I <sub>D</sub>	Continuous Drain Current	T <sub>C</sub> =25°C	91	A
		T <sub>C</sub> =100°C	58	
P <sub>D</sub>	Maximum Power Dissipation	T <sub>C</sub> =25°C	60	W
		T <sub>C</sub> =100°C	23.8	
I <sub>D</sub>	Continuous Drain Current	T <sub>A</sub> =25°C	16.7	A
		T <sub>A</sub> =70°C	13.3	
P <sub>D</sub>	Maximum Power Dissipation	T <sub>A</sub> =25°C	2	W
		T <sub>A</sub> =70°C	1.3	
I <sub>AS</sub> <sup>②</sup>	Avalanche Current, Single pulse	L=0.1mH	32	A
		L=0.5mH	19	
E <sub>AS</sub> <sup>②</sup>	Avalanche Energy, Single pulse	L=0.1mH	51	mJ
		L=0.5mH	90	

### Thermal Characteristics

Symbol	Parameter	Rating	Unit	
R <sub>θJC</sub>	Thermal Resistance-Junction to Case	Steady State	2.1	°C/W
R <sub>θJA</sub> <sup>③</sup>	Thermal Resistance-Junction to Ambient	Steady State	62.5	°C/W

Note ① : Max. current is limited by junction temperature

Note ② : UIS tested and pulse width are limited by maximum junction temperature 150°C

Note ③ : Surface Mounted on 1in<sup>2</sup> FR-4 board with 1oz

## N-Channel Electrical Characteristics (T<sub>J</sub>=25°C Unless Otherwise Noted)

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
<b>Static Electrical Characteristics</b>						
<b>BV<sub>DSS</sub></b>	Drain-Source Breakdown Voltage	V <sub>GS</sub> =0V, I <sub>DS</sub> =250uA	40	-	-	V
<b>I<sub>DSS</sub></b>	Zero Gate Voltage Drain Current	V <sub>DS</sub> =32V, V <sub>GS</sub> =0V	-	-	1	uA
<b>V<sub>GS(th)</sub></b>	Gate Threshold Voltage	V <sub>DS</sub> =V <sub>GS</sub> , I <sub>DS</sub> =250uA	1.2	1.7	2.4	V
<b>I<sub>GSS</sub></b>	Gate Leakage Current	V <sub>GS</sub> =±20V, V <sub>DS</sub> =0V	-	-	±100	nA
<b>R<sub>DS(ON)</sub></b> <sup>④</sup>	Drain-Source On-state Resistance	V <sub>GS</sub> =10V, I <sub>DS</sub> =25A	-	6	7.2	mΩ
		V <sub>GS</sub> =4.5V, I <sub>DS</sub> =15A		7.2	9.4	
<b>g<sub>fs</sub></b>	Forward Transconductance	V <sub>DS</sub> =5V, I <sub>DS</sub> =5A	-	17.5	-	S
<b>Dynamic Characteristics</b> <sup>⑤</sup>						
<b>R<sub>G</sub></b>	Gate Resistance	V <sub>GS</sub> =0V, V <sub>DS</sub> =0V, Freq.=1MHz	-	2.5	-	Ω
<b>C<sub>iss</sub></b>	Input Capacitance	V <sub>GS</sub> =0V, V <sub>DS</sub> =20V, Freq.=1MHz	-	1990	-	pF
<b>C<sub>oss</sub></b>	Output Capacitance		-	214	-	
<b>C<sub>rss</sub></b>	Reverse Transfer Capacitance		-	151	-	
<b>t<sub>d(ON)</sub></b>	Turn-on Delay Time	V <sub>GS</sub> =10V, V <sub>DS</sub> =20V, I <sub>D</sub> =1A, R <sub>GEN</sub> =6Ω	-	10	-	nS
<b>t<sub>r</sub></b>	Turn-on Rise Time		-	22.4	-	
<b>t<sub>d(OFF)</sub></b>	Turn-off Delay Time		-	69.2	-	
<b>t<sub>f</sub></b>	Turn-off Fall Time		-	25	-	
<b>Q<sub>g</sub></b>	Total Gate Charge	V <sub>GS</sub> =4.5V, V <sub>DS</sub> =35V, I <sub>D</sub> =25A	-	27.5	-	nC
<b>Q<sub>g</sub></b>	Total Gate Charge	V <sub>GS</sub> =10V, V <sub>DS</sub> =35V, I <sub>D</sub> =25A	-	52	-	
<b>Q<sub>gs</sub></b>	Gate-Source Charge		-	5.8	-	
<b>Q<sub>gd</sub></b>	Gate-Drain Charge		-	15	-	
<b>Source-Drain Characteristics</b>						
<b>V<sub>SD</sub></b> <sup>④</sup>	Diode Forward Voltage	I <sub>SD</sub> =4A, V <sub>GS</sub> =0V	-	0.7	1.1	V
<b>t<sub>rr</sub></b>	Reverse Recovery Time	I <sub>F</sub> =4A, V <sub>R</sub> =0V	-	19	-	nS
<b>Q<sub>rr</sub></b>	Reverse Recovery Charge	dI <sub>F</sub> /dt=100A/μs	-	11	-	nC

Note ④ : Pulse test (pulse width≤300us, duty cycle≤2%).

Note ⑤ : Guaranteed by design, not subject to production testing.

## N-Channel Typical Characteristics

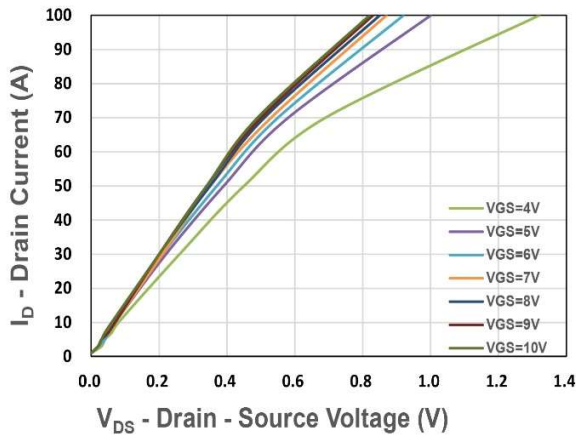


Figure 1. Output Characteristics

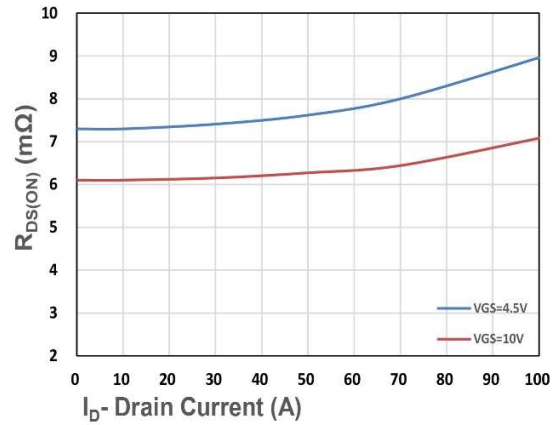


Figure 2. On-Resistance vs. ID

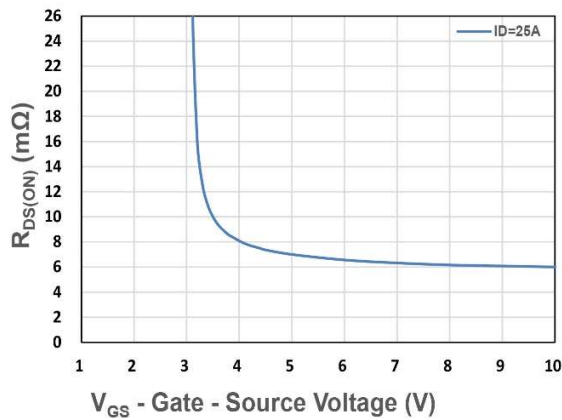


Figure 3. On-Resistance vs. VGS

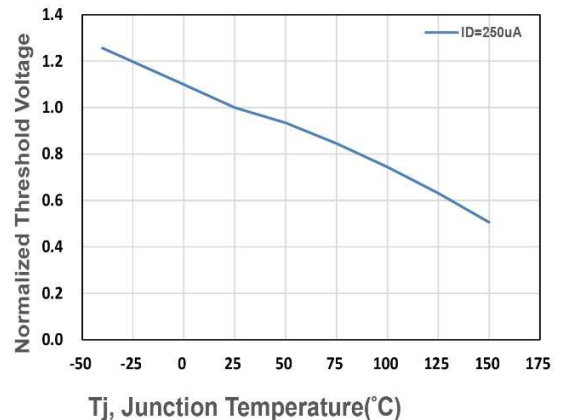


Figure 4. Gate Threshold Voltage

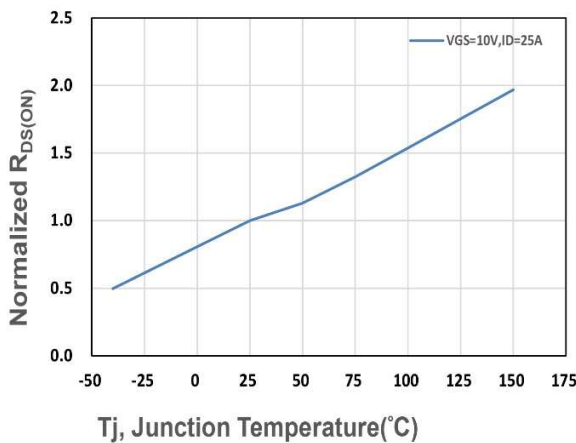


Figure 5. Drain-Source On Resistance

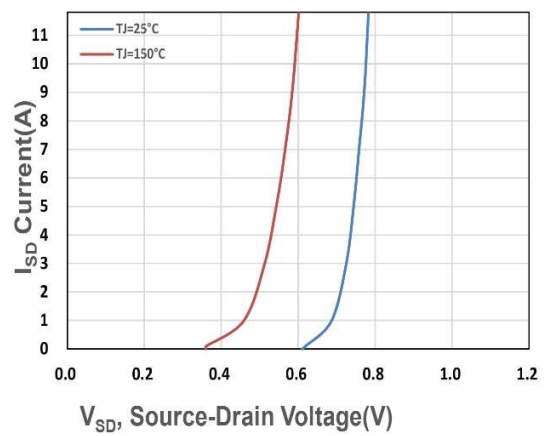


Figure 6. Source-Drain Diode Forward

# LM40072NAP3A

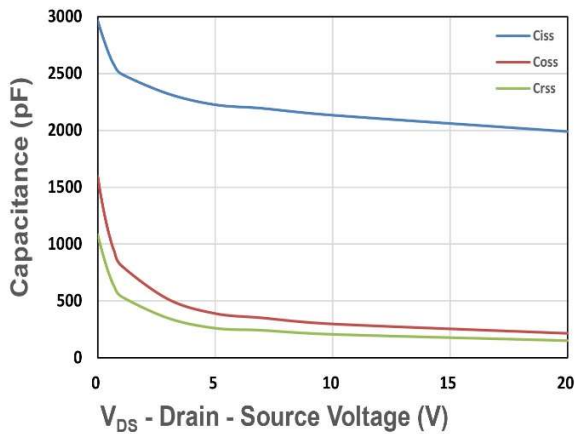


Figure 7. Capacitance

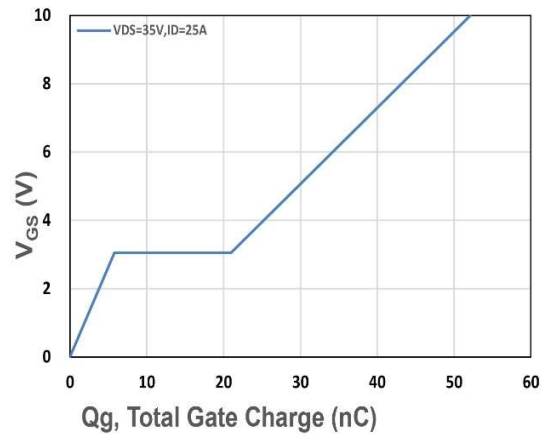


Figure 8. Gate Charge Characteristics

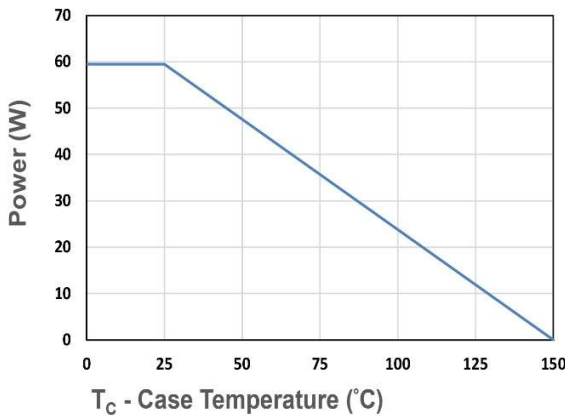


Figure 9. Power Dissipation

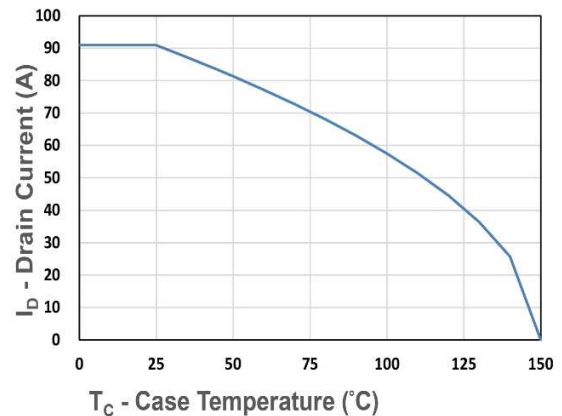


Figure 10. Drain Current

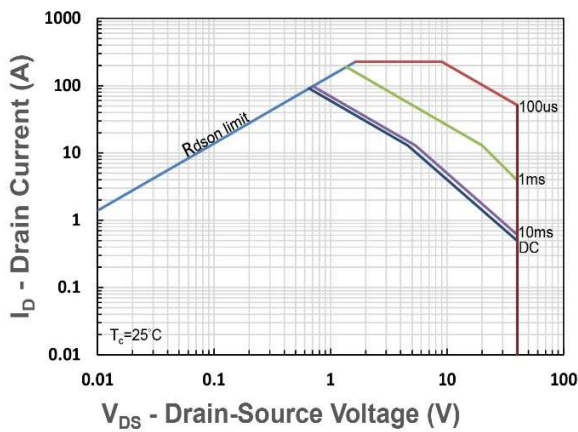


Figure 11. Safe Operating Area

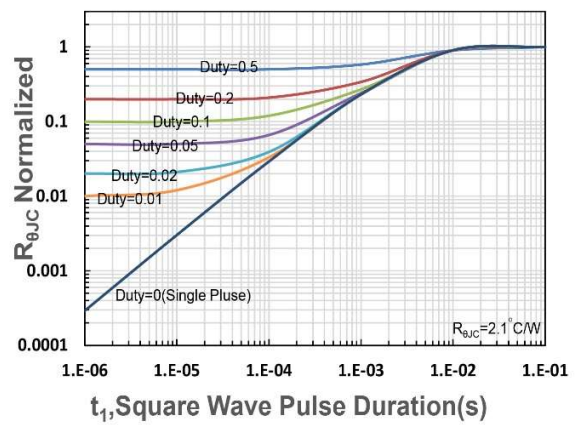


Figure 12.  $R_{\theta JC}$  Transient Thermal Impedance